Search Notes



Application/Control N

10581470

Applicant(s)/Patent Under Reexamination

LERCHE, THOMAS

Examiner

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
454	75, 76, 258	3/10/2008	PFO3
236	49.5	3/10/2008	PFO3
Above	Updated	12/20/2008	PFO3
454	305	12/20/2008	PFO3
Above	Updated	6/10/2009	PFO3

SEARCH NOTES

Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, USOCR, EPO, JPO DERWENT, IBM_TDB)	3/9/2008;	PFO3
searched - printout attached.	3/10/2008;	
	12/20/2008;	
	12/21/2008;	
	6/10/2009;	
	6/11/2009	
PLUS search performed - refer to search results in eDAN.	3/7/2008	STIC
Inventor name search performed in PALM and EAST.	3/10/2008	PFO3

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner